

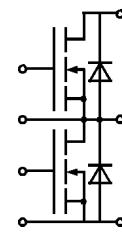
Absolute Maximum Ratings		Values	Units
Symbol	Conditions ¹⁾		
V_{DS}		100	V
V_{DGR}	$R_{GE} = 20 \text{ k}\Omega$	100	V
I_D	$T_{case} = 25^\circ\text{C} / 80^\circ\text{C}$	400 / 300	A
	$T_{case} = 100^\circ\text{C}$	250	A
I_{DM}	1 ms	1140	A
V_{GS}		± 20	V
P_D		1040	W
$T_j, (T_{stg})$		-40 ... +150 (125)	°C
V_{isol}	AC, 1 min., 200 μA	2 500	V
humidity	DIN 40 040	Class F	
climate	DIN IEC 68 T.1	40/125/56	
Inverse Diode			
$I_F = -I_D$		380	A
$I_{FM} = -I_{DM}$	10 μs	1140	A

SEMITRANS® M
Power MOSFET Modules
300 A, 100 V, 3,5 mΩ

SKM 313 B 010



SEMITRANS M3



Features

- N Channel, enhancement mode
- Short internal connections and low inductance case avoid oscillations
- Isolated copper baseplate using Al_2O_3 ceramic Direct Copper Bonding Technology (DCB)
- All electrical connections on top for easy busbaring
- Large clearance (13 mm) and creepage distances (20 mm)
- UL recognized file no. E63 532

Typical Applications

- DC servo and robot drives
- DC choppers
- Battery vehicles
- UPS equipment
- Plasma cutting
- Not suitable for linear amplification

This is an electrostatic discharge sensitive device (ESDS).
Please observe the international standard IEC 747-1, Chapter IX.

Suitable mounting hardware:
Ident No. 33321100
(for 10 SEMITRANS 3)
Screws → B 6 – 4

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
$V_{(BR)DSS}$	$V_{GS} = 0, I_D = 0,5 \text{ mA}$	100	–	–	V
$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 5 \text{ mA}$	2,1	3,0	4,0	V
I_{DSS}	$V_{GS} = 0$	–	–	100	μA
	$T_j = 25^\circ\text{C}$				
$I_{GSS}^{3)}$	$V_{DS} = 100 \text{ V}$	–	–	1000	μA
	$T_j = 125^\circ\text{C}$				
$R_{DS(on)}$	$V_{GS} = 20 \text{ V}, V_{DS} = 0$	–	–	100	nA
g_{fs}	$V_{GS} = 10 \text{ V}, I_D = 300 \text{ A}$	–	3	3,5	$\text{m}\Omega$
	$V_{DS} = 25 \text{ V}, I_D = 300 \text{ A}$	150	200	–	s
C_{CHC}		–	–	700	pF
C_{iss}	$V_{GS} = 0$	–	24	32	nF
C_{oss}	$V_{DS} = 25 \text{ V}$	–	7,3	11	nF
C_{rss}	$f = 1 \text{ MHz}$	–	4,3	6,5	nF
L_{DS}		–	–	20	nH
$t_{d(on)}$		–	100	–	ns
t_r	$I_D = 250 \text{ A}$	–	100	–	ns
$t_{d(off)}$	$V_{GS} = \pm 10 \text{ V}$	–	700	–	ns
t_f	$R_G = 4,7 \Omega$	–	250	–	ns
Inverse Diode					
V_{SD}	$I_F = 300 \text{ A}, V_{GS} = 0 \text{ V}$	–	1,2	1,5	V
t_{rr}	$T_j = 25^\circ\text{C}^{3)}$	–	160	–	ns
	$T_j = 150^\circ\text{C}^{3)}$	–	–	–	ns
Q_{rr}	$T_j = 25^\circ\text{C}^{3)}$	–	10	–	μC
I_{RR}	$T_j = 150^\circ\text{C}^{3)}$	–	–	–	A
Thermal characteristics					
R_{thjc}	per MOSFET	–	–	0,12	$^\circ\text{C}/\text{W}$
R_{thch}	M ₁ , surface 10 μm , per module	–	–	0,038	$^\circ\text{C}/\text{W}$

Mechanical Data				
M ₁	to heatsink, SI Units (M6)	3	–	5 Nm
	to heatsink, US Units	27	–	lb.in.
M ₂	for terminals, SI Units (M6)	2,5	–	Nm
	for terminals, US Units	22	–	lb.in.
a		–	–	5x9,81 m/s ²
w		–	–	325 g
Case	→ B 5 – 46		D 56	

¹⁾ $T_{case} = 25^\circ\text{C}$, unless otherwise specified

³⁾ $I_F = 300 \text{ A}, V_R = 100 \text{ V}, -di_F/dt = 100 \text{ A}/\mu\text{s}$

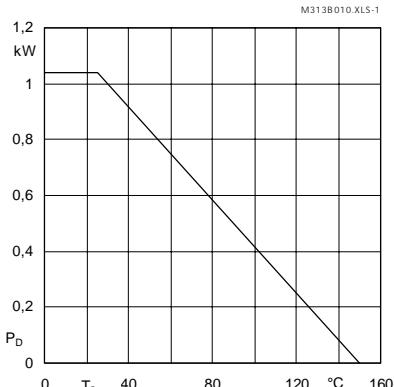


Fig. 1 Rated power dissipation vs. temperature

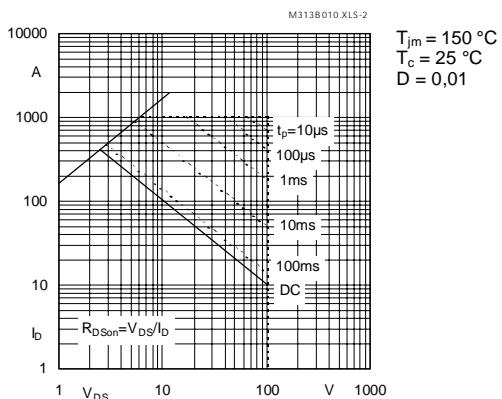


Fig. 2 Maximum safe operating area, single pulse

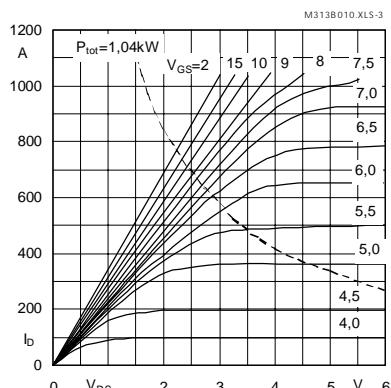


Fig. 3 Output characteristic, $t_p = 80 \mu\text{s}$, $T_j = 25^\circ\text{C}$

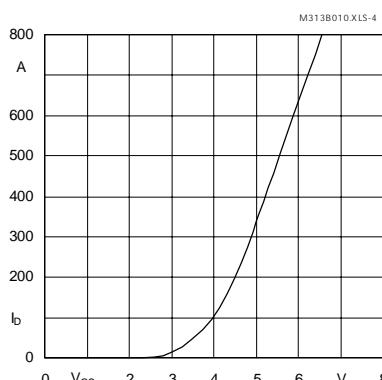


Fig. 4 Transfer characteristic, $t_p = 80 \mu\text{s}$, $V_{DS} = 25 \text{ V}$

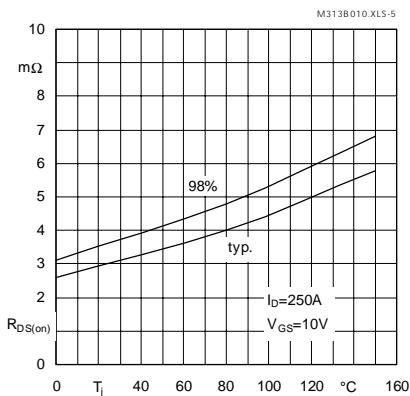


Fig. 5 On-resistance vs. temperature

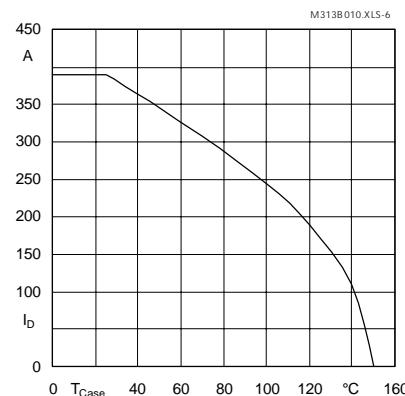


Fig. 6 Rated current vs. temperature

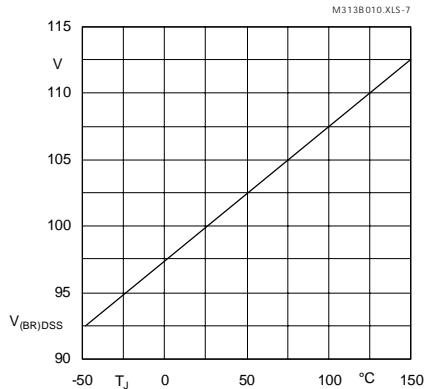


Fig. 7 Breakdown voltage vs. temperature

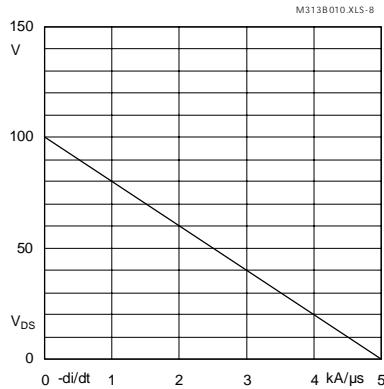


Fig. 8 Drain-source voltage derating (L_{DS})

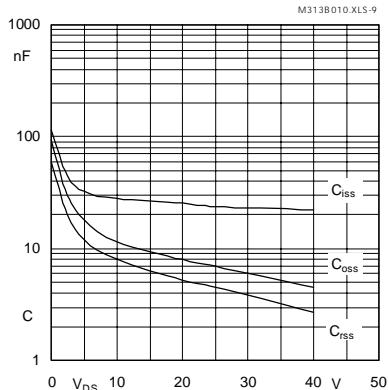


Fig. 9 Typ. capacitances vs. drain-source voltage

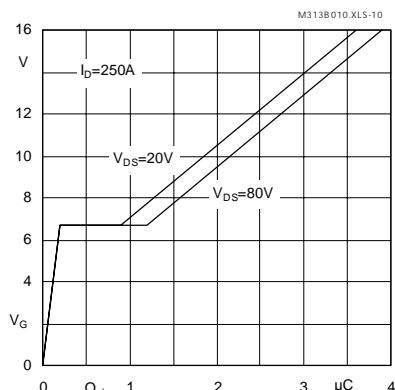


Fig. 10 Gate charge characteristic, $I_{Dp} = 250$ A

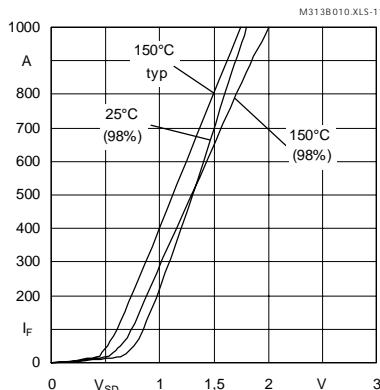


Fig. 11 Typ. Diode forward characteristic, $t_p = 80$ μs

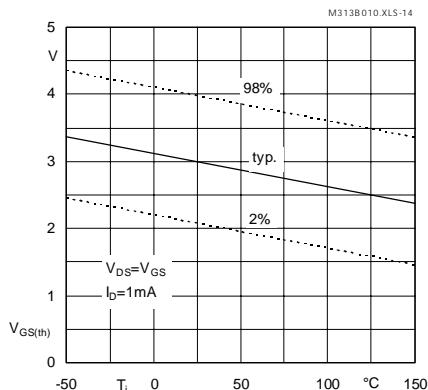


Fig. 14 Gate-source threshold voltage

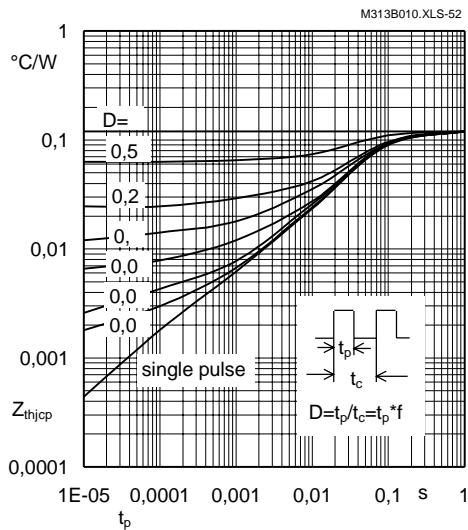


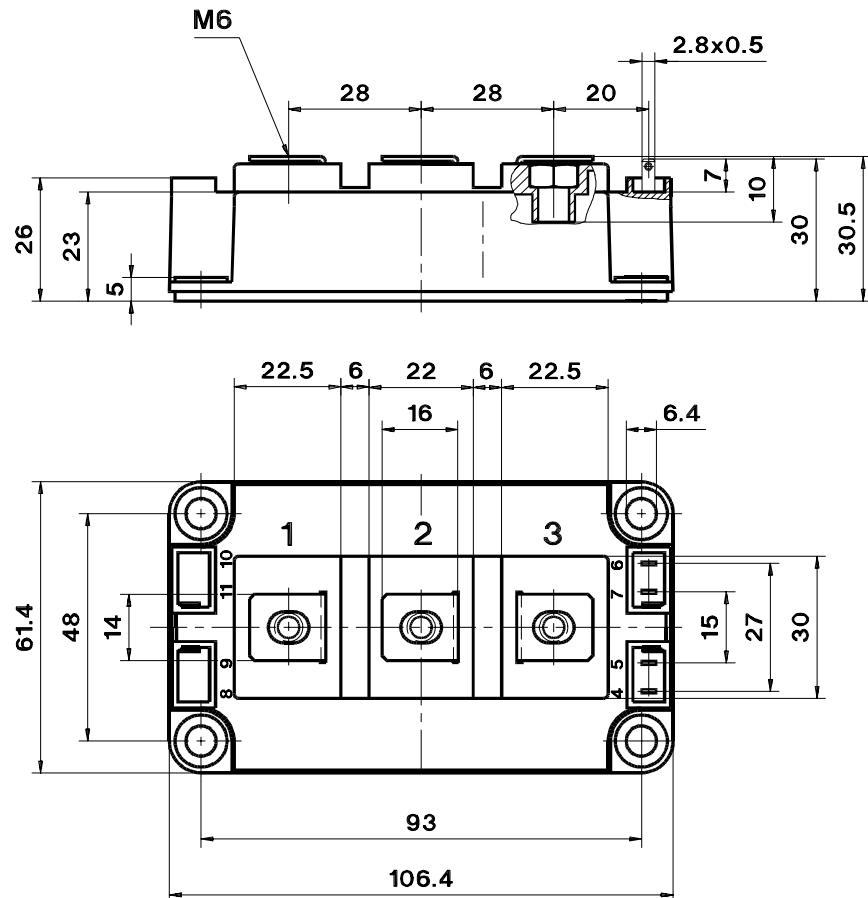
Fig. 52 Thermal impedance under pulse conditions

SEMITRANS M 3

Case D 56

SKM 313 B 010

CASED56



Dimensions in mm